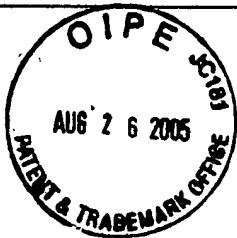


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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE	
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT	Atty. Docket No. UBAT1490-1



Applicant(s) Gregory R. Hanson et al.	
Application Number 10/607,824	Date Filed June 27, 2003
For RECORDING MULTIPLE SPATIALLY- HETERODYNED DIRECT-TO-DIGITAL HOLOGRAMS IN ONE DIGITAL IMAGE	
Group Art Unit 2621	Examiner
Confirmation Number: 8424	

Mail Stop Amendment
Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Dear Sir:

<p align="center"><u>Certificate of Mailing Under 37 C.F.R. 1.8</u></p> <p>I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313 on <u>Aug 24</u>, 2005.</p> <p align="center"> John J. Bruckner</p>

Applicant respectfully requests, pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, that the reference(s) listed on the attached PTO/SB/08A and/or PTO/SB/08B forms be considered and cited in the examination of the above-identified application. Pursuant to 37 C.F.R. §§ 1.97(g) and (h), no representation is made that a search has been made or that this art is material to the patentability of the present application. Copies of the non-US patent references are enclosed for the convenience of the Examiner.

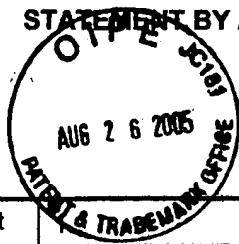
While Applicants believe no (further) fees are due, if any (further) fees are due, the Commissioner is hereby authorized to charge any fees or credit any overpayments to Deposit Account No. 50-3204 of John Bruckner PC.

Dated: Aug 24, 2005

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Respectfully submitted,

Attorneys for Applicant
John J. Bruckner
Reg. No. 35,816

INFORMATION DISCLOSURE STATEMENT BY APPLICANT 				Application Number		10/607,824	
				Filing Date		June 27, 2003	
				First Named Inventor		Gregory R. Hanson	
				Group Art Unit		2621	
				Examiner Name			
Sheet		of 1		Attorney Docket		UBAT1490-1	
U.S. PATENT DOCUMENTS							
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		Number	Kind Code (if known)				
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		Country Code	Number	Kind Code (if known)			
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Examiner Signature					Date Considered		

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				Group Art Unit	2621	
				Examiner Name		
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